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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/074,624	02/13/2002	Yoshikazu Nakayama	57A 3216	7347
75	90 09/03/2004		EXAM	INER
KODA & ANDROLIA			JAGAN, MIRELLYS	
2029 Century Park East Suite 1430			ART UNIT	PAPER NUMBER
Los Angeles, CA 90067-3024			2859	

DATE MAILED: 09/03/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

		pra .
	Application No.	Applicant(s)
0.65	10/074,624	NAKAYAMA ET AL.
Office Action Summary	Examiner	Art Unit
	Mirellys Jagan	2859
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the	he correspondence address
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a repl - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, may a reply ly within the statutory minimum of thirty (30 will apply and will expire SIX (6) MONTHS e. cause the application to become ABAND	be timely filed) days will be considered timely. from the mailing date of this communication. ONED (35 U.S.C. § 133).
Status		
 1) ⊠ Responsive to communication(s) filed on 8/5/0 2a) ☐ This action is FINAL. 2b) ⊠ This 3) ☐ Since this application is in condition for alloware closed in accordance with the practice under Exercise. 	s action is non-final. nce except for formal matters,	
Disposition of Claims		
4) ☐ Claim(s) 1-8 is/are pending in the application. 4a) Of the above claim(s) is/are withdra 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-8 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or		
Application Papers		
9)☐ The specification is objected to by the Examine 10)☑ The drawing(s) filed on 13 February 2002 is/an Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11)☐ The oath or declaration is objected to by the Ex	e: a)⊠ accepted or b)⊡ obje drawing(s) be held in abeyance. tion is required if the drawing(s) is	See 37 CFR 1.85(a). s objected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Burea * See the attached detailed Office action for a list	ts have been received. ts have been received in Appli prity documents have been rec u (PCT Rule 17.2(a)).	ication No eived in this National Stage
Attachment(s)	□	(DTO 442)
Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date		mary (PTO-413) ail Date nal Patent Application (PTO-152)

DETAILED ACTION

Claim Objections

- 1. Claims 7 and 8 are objected to because of the following informalities:
 - In claim 7, "heat emitting probe" should be changed to --heat emitting body-- in line 3.

In claims 7 and 8, it is not clear how the thermal conductivity and temperature distributions are detected since these claims and their intervening claims fail to claim any element or means for detecting changes in radiant heat and resistance to detect the thermal conductivity and temperature distributions. Therefore, claims 7 and 8 appear to be reciting the intended use of the probe apparatus claimed in claim 5, which apparently has a structure that is capable of detecting changes in radiant heat and resistance to detect the thermal conductivity and temperature distributions. Appropriate correction is required.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1-8 are rejected under 35 U.S.C. 103(a) as being unpatentable over the prior art disclosed by Applicant on pages 1-2 of the specification [hereinafter Prior Art] in view of U.S. Patent Application Publication 2002/0084410 to Colbert et al [hereinafter Colbert].

The Prior Art teaches a conventional heat-emitting probe comprising:

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an AFM cantilever (2);

a pyramid tip (8) protruding from the tip end of the cantilever;

electrode films (5, 5c, 6, and 6c) provided on both side surfaces of the of the cantilever and the side surfaces of the pyramid tip (8); and

a control circuit connected to the electrode films, the circuit comprising a power supply (20) for supplying an electric current to the tip via the electrode films;

wherein the electric current is caused to pass between the electrode films by the power supply to heat the tip so that it emits heat while it is moved to scan (i.e., a scanning mechanism moves it) the surface of a recording medium to record information on the medium by forming a hole pattern in the surface (see figure 9).

The Prior Art does not disclose the probe having a conductive carbon nanotube probe needle fastened to the pyramid tip, the carbon nanotube needle having a heat emitting body attached to its outer circumferential surface, wherein the body and the needle are connected to the electrode films by lead wires connected thereto for receiving the electric current from the electrode films to heat the needle.

Colbert discloses an AFM probe comprising a cantilever having a pyramid tip thereon, wherein the tip has a conductive carbon nanotube probe needle fastened to the pyramid tip.

Colbert teaches that is beneficial to provide a conventional pyramid tip of an AFM probe with a carbon nanotube since the small size of the nanotube allows the probe to sense, measure, analyze, and modify objects more accurately with nanometer resolution and nanometer dimensions (see paragraphs 3-5, 9, 11-13, and 37).

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Referring to claims 1 and 2, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the probe of the Prior Art by fastening a conductive carbon nanotube probe needle to the pyramid tip, as taught by Colbert, in order for the probe to modify the medium more accurately with nanometer resolution and nanometer dimensions.

Furthermore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the probe of the Prior Art and Colbert by electrically connecting the conductive needle to the electrode films of the probe using conventional means such as wires and conductive material in order to heat the needle so that the new nano-sized tip can emit the heat needed to record the information on the medium.

Referring to claims 7 and 8, claims 7 and 8 recite are considered to recite the intended use of the claimed probe apparatus, as stated above in paragraph 1. A recitation of the intended use of the claimed invention, in this case the claimed probe apparatus, must result in a structural difference between the claimed invention and the prior art in order to patentably distinguish the claimed invention from the prior art. Therefore, since the structure of the probe apparatus of the Prior Art and Colbert is capable of performing the intended use, then it meets these claims. See In re Casey, 152 USPQ 235 (CCPA 1967) and In re Otto, 136 USPQ 458, 459 (CCPA 1963).

Response to Arguments

4. Applicant's arguments with respect to claims 1-8 have been considered but are moot in view of the new ground(s) of rejection.

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Conclusion

5. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

The following patents and publications disclose a carbon nanotube tip for an AFM:

U.S. Patent 6,159,742 to Lieber et al

U.S. Patent 6,146,227 to Mancevski

U.S. Patent 6,528,785 to Nakayama et al

U.S. Patent Application Publication 2002/0112814 to Hafner et al

U.S. Patent Application Publication 2002/0122766 to Lieber et al

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Mirellys Jagan whose telephone number is 571-272-2247. The examiner can normally be reached on Monday-Friday from 9AM to 4PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Diego Gutierrez can be reached on 571-272-2245. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Diego Gutierrez Supervisory Patent Examiner Technology Center 2800